## IN THE CLAIMS

Please amend the following claims which are pending in the present application:

31. (Twice Amended) A gate electrode comprising:

an insulative layer disposed on a substrate;

a gate layer disposed on said insulative layer;

thin first spacers disposed adjacent to opposite sides of said gate layer;

thin second spacers disposed adjacent to opposite sides of said thin first

spacers;

thin third spacers disposed adjacent to opposite sides of said thin second spacers;

thick fourth spacers disposed adjacent to opposite sides of said thin third spacers; and

a conductive layer disposed on said gate layer, extending beyond edges of said gate layer and having a lower side at least as high as upper edges of said first, second, third, and fourth spacers.

- 32. (Amended) The gate electrode of claim 31 wherein said insulative layer comprises an oxide.
- 33. (Amended) The gate electrode of claim 32 wherein said gate layer comprises a polysilicon.

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34. (Amended) The gate electrode of claim 33 wherein said conductive layer comprises a polycide.

35. (Amended) The gate electrode of claim 34 wherein said thin first spacers comprise an oxide.

36. (Amended) The gate electrode of claim 35 wherein said thin second spacers comprise a nitride.

37. (Amended) The gate electrode of claim 36 wherein said thin third spacers comprise an oxide.

38. (Amended) The gate electrode of claim 37 wherein said thick fourth spacers comprise a nitride.

39. (Amended) The gate electrode of claim 38 wherein said polycide comprises titanium salicide (TiSi<sub>2</sub>).

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